

L Number	Hits	Search Text	DB	Time stamp
1	116514	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3))	USPAT; EPO; JPO; DERWENT	2003/02/13 11:19
2	1	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3)) and (plurality or multiple or several) adj20 (chips adj10 integrally adj10 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 09:50
4	1	(plurality or multiple or several) adj20 (chips adj10 integrally adj10 sealed) and test\$3	USPAT; EPO; JPO; DERWENT	2003/02/13 09:52
3	5	(plurality or multiple or several) adj20 (chips adj10 integrally adj10 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 09:55
5	25653	(plurality or multiple or several) adj20 (chips or IC)	USPAT; EPO; JPO; DERWENT	2003/02/13 09:58
6	122	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3)) same (plurality or multiple or several) adj20 (chips or IC))	USPAT; EPO; JPO; DERWENT	2003/02/13 09:59
7	2897	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3)) and (plurality or multiple or several) adj20 (chips or IC))	USPAT; EPO; JPO; DERWENT	2003/02/13 09:58
8	1089	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3)) and (plurality or multiple or several) adj20 (chips or IC)) and pins	USPAT; EPO; JPO; DERWENT	2003/02/13 09:59
10	24	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3)) same (plurality or multiple or several) adj20 (chips or IC)) and pads and pins	USPAT; EPO; JPO; DERWENT	2003/02/13 10:39
11	5	513188.pn.	USPAT; EPO; JPO; DERWENT	2003/02/13 10:39
12	2	5513188.pn.	USPAT; EPO; JPO; DERWENT	2003/02/13 10:39
13	1	5513188.pn.and pins and pads	USPAT; EPO; JPO; DERWENT	2003/02/13 10:39
9	507	((JTAG adj3 test\$3) or (IEEE 1149.1) or (boundary adj2 scan adj3 test\$3)) and (plurality or multiple or several) adj20 (chips or IC)) and pins and pads	USPAT; EPO; JPO; DERWENT	2003/02/13 11:19
14	963	(boundary adj2 scan adj3 test\$3)	USPAT; EPO; JPO; DERWENT	2003/02/13 11:20
15	149	(boundary adj2 scan adj3 test\$3) and (plurality or multiple or several) adj20 (chips or IC))	USPAT; EPO; JPO; DERWENT	2003/02/13 11:20
16	84	(boundary adj2 scan adj3 test\$3) and (plurality or multiple or several) adj20 (chips or IC)) and pad\$1 and pin\$1	USPAT; EPO; JPO; DERWENT	2003/02/13 12:20
17	215	TDI adj5 pin	USPAT; EPO; JPO; DERWENT	2003/02/13 12:33
18	2	(TDI adj5 pin) same pad	USPAT; EPO; JPO; DERWENT	2003/02/13 12:29
19	4	(TDI adj5 pin\$1) same pad\$1	USPAT; EPO; JPO; DERWENT	2003/02/13 12:29
20	130	(TDI adj10 pin\$1) and pad\$1 and (TDO)	USPAT; EPO; JPO; DERWENT	2003/02/13 13:25
21	90	(TDI same TAP same TDO) and ((plurality or multiple) same (chips or ICs))	USPAT; EPO; JPO; DERWENT	2003/02/13 13:28

22	76	(TDI same TAP same TDO) and ((plurality or multiple) near10 (chips or ICs))	USPAT; EPO; JPO; DERWENT	2003/02/13 14:03
23	0	(TDI same TAP same TDO) and ((plurality or multiple) near10 (chips or ICs)) and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:04
25	3	((plurality or multiple) near10 (chips or ICs)) and (integrally adj5 sealed) and testing	USPAT; EPO; JPO; DERWENT	2003/02/13 14:05
24	13	((plurality or multiple) near10 (chips or ICs)) and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:11
26	0	TDO and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:07
27	17	Tap and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:07
28	4	(scan adj3 test\$3) and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:10
29	15	(scan) and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:10
30	17	((plurality or multiple) same (chips or ICs)) and (integrally adj5 sealed)	USPAT; EPO; JPO; DERWENT	2003/02/13 14:18